INTEGRALEED

MODEL BDL800IR AND BDL600IR WITH INTEGRAL SHUTTER

CONVENTIONAL BACK-DISPLAY LEED-AES SPECTROMETER FEATURING UNIQUE DESIGN AND PERFORMANCE:



HIGH ENERGY & IMAGE RESOLUTION FOR LEED AND AES

MINIATURE ELECTRON GUN WITH DOUBLE FOCUSING

SUITABLE FOR "IN SITU" GROWTH MONITORING

INTEGRAL LINEAR MOTION AND SHUTTER

LOW OUTGASSING RATE



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SPECIFICATIONS

LEED-AUGER OPTICS (Models BDL600IR and BDL800IR)

Fused silica glass coated with indium-tin oxide conductive layer Glass-Display and P31 phosphor (ZnS:Ag:Cu-green, 525 nm wavelength) 90° angle of acceptance from sample at a distance of 50 mm BDL600IR.....

BDL800IR..... 100° angle of acceptance from sample at a distance of 75 mm

Concentric assembly of hemispherical grids Retarding Field Analyzer

BDL600IR..... Working distance from sample 15 mm BDL800IR..... Working distance from sample 18 mm

Grid Material..... Gold coated tungsten wire mesh (100 mesh, 81% transparency)

Energy Resolution..... 0.2% - 0.5% at low modulation volt.

Monitoring 6" or 8" standard viewport Up to 150 mm retraction from sample (100mm standard); linear **Linear Motion**

ball bearing and acme thread with all spring electr. connections

Integral Shutter Open and close at any position of the linear motion Magnetic Shielding Mu-metal cylinder with front cover for maximum atteniuation Extreme-high-vacuum compatibility with stainless steel, high Assembly

alumina and Au-plated copper alloy materials

Mounting 6" (CF100) or 8" (CF150) double sided conflat flange with

sample distance 145 mm - 500 mm Bakeability Under vacuum, 250° C maximum

INTEGRAL MINIATURE ELECTRON GUN

Beam Energy LEED - 5 eV to 750 eV

AES to 3000 eV

Beam Current LEED - 2 µA at 100 eV and 0.5 mm beam size

AES - up to 100 µA at 3 keV

Beam Size

Electron Source Tungsten-2%Thoriated filament standard,

single crystal LaB6 filament optional **Energy Spread** 0.45 eV (thoriated-tungsten filament)

ORDERING GUIDE

BDL800IR-CP Complete LEED-Auger package with 8"

flange(incl. LMX, ISH, V800,

LPS300, LOA10-AES, LIM08)

Complete LEED-Auger package with 6" BDL600IR-CP

flange (incl. LMX, ISH, V600, LPS300, LOA10-AES, LIM08)

BDL800IR LEED optics with integral electron gun

on 8" flange (Specify 3 or 4 grid)

BDL600IR LEED optics with integral electron gun on

6" flange (Specify 3 or 4 grid)

LMX Linear motion (X=retraction distance)

ISH Integral shutter V800 8" viewport

V600 6" viewport

LPS075 Power supply with voltage range 0 - 750V LPS300 Power supply with voltage range 0 - 3kV AES-Ser AES software for external Lock-in Ampl.

LIM08 LEED imaging software with CCD camera,

full version

LIM08B LEED imaging software with CCD camera,

basic version

LOA10-AES Digital AES controller with ramp voltage.

sinewave oscillator, lock-in and AES

software

LOA100 External Lock-in Amplifier

RVO Ramp Voltage and oscillator from 1 mm to 250 µm - adjusted by wehnelt potential, limited by exchangeable aperture down to 50 µm

Overall Size 10 mm lens diameter and 80 mm length OPTICS FULLY EXTENDED FLANGE O.D MONITORING SIDE

WD (WORKING DISTANCE) BDL800/600/450-LMX length calculation

MODEL	FLANGE SIZES EUROPEAN NORTH AMERICAN SIZE		DIMENSIONS							
			Α	В	Е	WD	С	Optics lenght - fully extended with 100mm retraction	FS - fully extended with 100mm retraction	FORMULA
BDL800	DN150	CF8*	Ø203mm	Ø142mm	Ø57mm	18mm	127mm	355mm	373mm	FS = 173mm + 2 LMX - OV
BDL600	DN100	CF6"	Ø152mm	Ø94mm	Ø44.5mm	15mm	108mm	335.5mm	350.5mm	FS = 150.5mm + 2 LMX - O\
BDL450	DN63	CF4.5"	Ø114mm	Ø57mm	Ø30.5mm	10mm	114mm			
MCP-LEED						•	•	•		•
BDL800-MCP-100DEG	DN150	CF8"	Ø203mm	Ø142mm	Ø38mm	10mm	124mm	355.5mm	365.5mm	FS = 165.5mm + 2 LMX - O\
BDL800-MCP-77DEG	DN150	CF8"	Ø203mm	Ø142mm	Ø44.5mm	15mm	127mm	358mm	373mm	FS = 173mm + 2 LMX - OV
BDL600-MCP-72DEG	DN100	CF6"	Ø152mm	Ø94mm	Ø44.5mm	15mm	108mm	335.5mm	350.5mm	FS = 150.5mm + 2 LMX - O\

NL - Nipple (optional)

NOTE:

- If the calculated Flange Sample length FS is shorter than the actual Port length of the UHV chamber, the addition of the Nipple adaptor is required The Nipple length (NL) can be calculated: NL= FS - actual port length of UHV chamber.
- If the calculated Flange Sample length FS is longer than the actual Port length of the UHV chamber, the holding posts are extended.
- Flange to Sample distance
 - (required port length for given retraction distance)
- WD - Working distance LMX - Retraction distance
 - overlapping (from 0 to 10mm)
- (with overlapping the LEED optics is not fully extended in the operating position)